Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/767,765	OGAWA, HIDEHIKO	GAWA, HIDEHIKO	
Examiner	Art Unit		
Thomas D. Lee	2625		

SEARCHED				
Class	Subclass	Date	Examiner	
358	1.15, 402, 440	12/8/2005	TDL	
379	100.01	12/8/2005	TDL	
379	100.08	12/8/2005	TDL	
379	100.13	12/8/2005	TDL	
379	100.17	12/8/2005	TDL	
updated		5/23/2006	TDL	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			,	
Interferen Prin	ce Search tout	5/23/2006	TDL	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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